

Application/Control No.	Applicant(s)/Pate Reexamination	ent under
09/770,599	MILLER ET AL.	
Examiner	Art Unit	
Tan Dean D. Nguyen	3629	

SEARCHED					
Class	Subclass	Date	Examiner		
705		7/05	on		
	10		1		
	11				
	26				
	27	W/	4		
_					
	i				

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	1		;		
	·				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
US	7/05	Dn
US 1. PG 2. Patent		
FOREIGN		
FOREIGN 1. JPB 2. EPO 3. Derment	- .	
NPL		
Ffeet 1	1	
NPL Pfest! Pfest2 VFfest		
		•
:		
		-